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Low-energy electron microscopy on two-dimensional systems : growth, potentiometry and band structure mapping

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Electronic circuits

In this appendix the electronic circuits used for potentiometry measurements can be found.

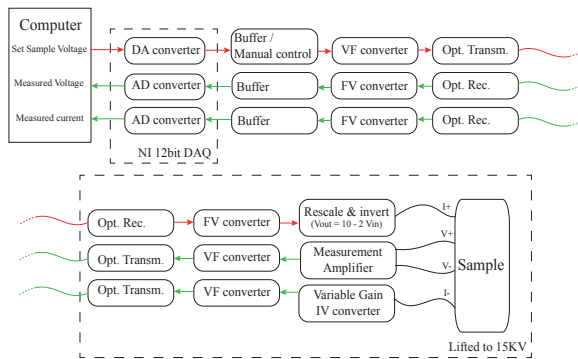


Fig. A.1: Diagram showing how signals travel from the computer to the sample and back. Electronic diagrams for the individual components can be found in the subsequent figures.

A. ELECTRONIC CIRCUITS

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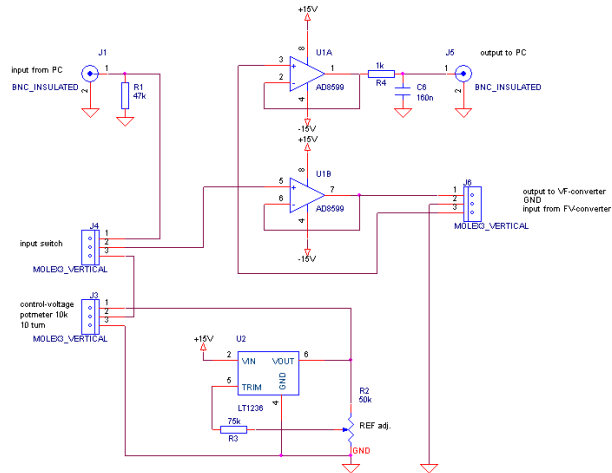


Fig. A.2: Electronic diagram for the buffer and the manual control

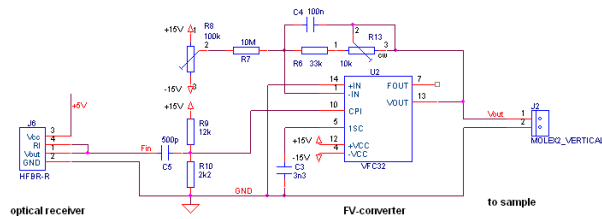


Fig. A.3: Electronic diagram for the frequency to voltage converter

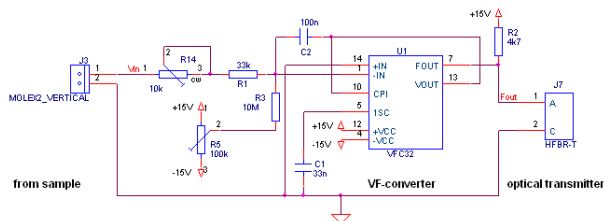


Fig. A.4: Electronic diagram for the voltage to frequency converter

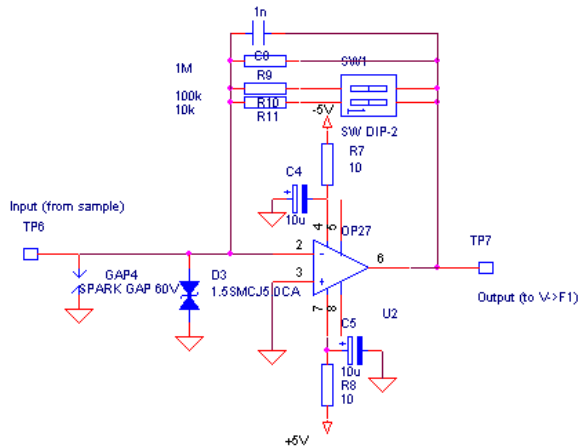


Fig. A.5: Electronic diagram for the iv-converter

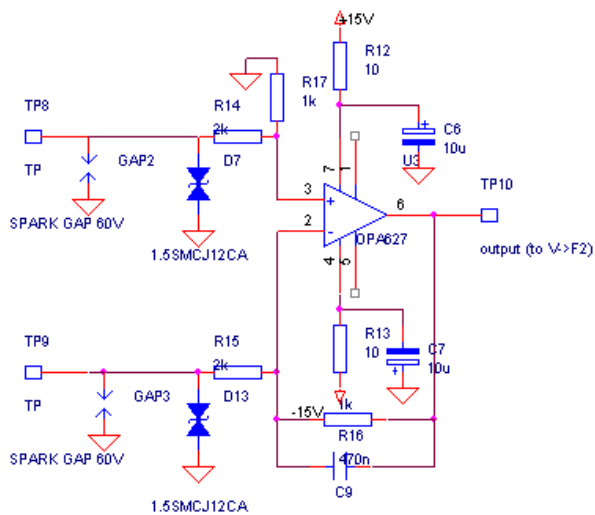


Fig. A.6: Electronic diagram for the measurement amplifier

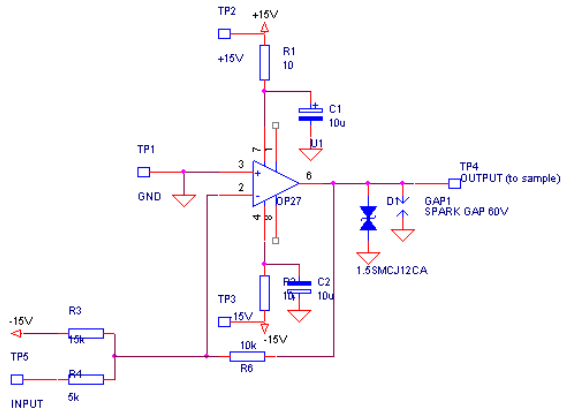


Fig. A.7: Electronic diagram for the rescaling of the 0-10 V signal of the FV-converter to a -10-10V signal.